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Substitute for form 1449A/B/PTO		Complete if Known			
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	10/672,961 (Conf. No. 9439)		
		Filing Date	September 26, 2003		
		First Named Inventor	Glenn J. Leedy		
		Art Unit	2822		
		Examiner Name	Monica Lewis		
Sheet	1	of	2	Attorney Docket Number	ELM-2 Cont. 4

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
		Number-Kind Code ² (if known)				
ML		US 3,636,358	01/18/1972	Groschwitz		
		US 3,932,932	01/20/1976	Goodman		
		US 4,028,547	06/07/1977	Eisenberger		
		US 4,393,127	07/12/1983	Greschner et al.		
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		US 2005-0023656	02/03/2005	Leedy		
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Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ² -Number ³ -Kind Code ⁴ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		DE3293193	03-17-1983	Mitsubishi Electric Corp.	
		JP2037655	02-07-1990	Siemens AG	
		JP3127846	05-30-1991	Canon KK	
		JP3174745	07-29-1991	Fujitsu Limited	
		WO 98/49337	09-07-1998	Trusi Technologies, LLC	

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Examiner Signature		Date Considered	1/14/07
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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		Wolf, Stanley and Richard N. Tauber; <u>Silicon Processing For the VLSI Era. Volume 1: Process Technology</u> ; Sunset Beach, CA: Lattice Press, 1986, pages 191-194	
		European Search Report for Application No. EP-02-00-9643 (date completed: October 8, 2002)	
		Phys. Rev. B., Condens. Matter Mater. Phys. (USA). Physical Review B (Condensed Matter and Materials Physics), 15 March 2003, APS through AIP, USA.	
		S. Wolf, <u>Silicon Processing For the VLSI Era</u> , 1990, Lattice Press, Volume 2, page 191.	
		Svechnikov, S.V.; Kobylvatskaya, M.F.; Kimarskii, V.I.; Kaufman, A.P.; Kuzolev, Yu. I.; Cherepov, Ye. I.; Fomin, B.I.; "A switching plate with aluminium membrane crossings of conductors"; 1972	
		Salazar, M.; Wilkins, C.W., Jr.; Ryan, V.W.; Wang, T.T.; "Low-stress films of cyclized polybutadiene dielectrics by vacuum annealing"; Oct. 21-22, 1986; pp. 96-102.	
		Allen, Mark G.; Senturia, Stephen D.; "Measurement of polyimide interlayer adhesion using microfabricated structures"; 1988; pp. 352-356.	
		Kochugova, I.V.; Nikolaeva, L.V.; Vakser, N.M., (M.I. Kalinin Leningrad Polytechnic Institute (USSR); "Electrophysical investigation of thin-layered inorganic coatings"; 1989; pp. 826-828.	

/TD/ 3/7/10

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Examiner Signature		Date Considered	11/10/03
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